Notice of Allowability	Application No.	Applicant(s)	
	10/727,081	COUMOU ET AL.	
	Examiner	Art Unit	
	Carol S. Tsai	2857	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to *5/24/05*.

2. ☒ The allowed claim(s) is/are *1-20*.

3. ☒ The drawings filed on *02 December 2003* are accepted by the Examiner.

4. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
   a) ☐ All b) ☐ Some* c) ☐ None of the:
      1. ☐ Certified copies of the priority documents have been received.
      2. ☐ Certified copies of the priority documents have been received in Application No. _____ .
      3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

   * Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.

6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
   (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
      1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
   (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

   Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).

7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☒ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)
3. ☒ Information Disclosure Statements (PTO-1449 or PTO/SB/08), Paper No./Mail Date 3/31/2005 & 3/29/04
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date _____ .
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____.

DETAILED ACTION

Allowable Subject Matter

1. Claims 1-20 are allowed.

2. The following is an examiner's statement of reasons for allowance:

U. S. Publication 2004/0253921 to Turner is the reference closest to the claimed invention. Turner discloses a radio frequency (RF) metrology system for monitoring output of an RF generator to a load comprising: a sensor component, the sensor sensing at least one of a voltage and current applied to a load; an analysis module component, the analysis module component receiving at least one of a voltage and current sensor signal from the sensor component; wherein one of the sensor component and the analysis module component may be replaced while the other component remains installed and wherein the RF metrology system is recalibrated following replacement of the one component. However, Turner does not teach a sensor, the sensor sensing at least one of a voltage or current applied to a load; an analysis module, the analysis module receiving at least one of a voltage sensor signal or current sensor signal from the sensor; wherein at least one of sensor or the analysis module is replaceable while the other of the sensor or analysis module remains installed and wherein the RF metrology system recalibrated following replacement of the other of the sensor or analysis module; and including all of the other limitations in the respective independent claims.

U. S. Publication 2004/0253921 to Turner in view of U. S. Patent No. 5,737,496 to Frye et al. and U. S. Patent No. 6,326,584 to Jewett et al. are references closest to the claimed invention. Turner in combination with Frye et al. and Jewett et al. disclose a method for

replacing components of an RF metrology system for monitoring output of an RF generator to a load comprising the steps of: providing a RF system including a base sensor and a base analysis module; calibrating a base RF metrology system; determining a frequency response characteristic of the base sensor; determining a set of calibration coefficients; and generating a scaling matrix in accordance with the calibration coefficients. However, Turner in combination with Frye et al. and Jewett et al. do not teach determining a response characteristic of the base analysis module; characterizing a frequency response of a group of sensors other than the base sensor; and determining a set of calibration coefficients in accordance with at least one of the response characteristic or the frequency response; and including all of the other limitations in the respective independent claims.

U. S. Publication 2004/0253921 to Turner in view of U. S. Patent No. 6,326,584 to Jewett et al. are references closest to the claimed invention. Turner in combination with Jewett et al. disclose a method for replacing components of an RF metrology system for monitoring output of an RF generator to a load comprising the steps of: providing a RF system including a base sensor and a base analysis module; calibrating a base RF metrology system; determining a frequency response characteristic of the base sensor; and determining a set of calibration coefficients. However, Turner in combination with Jewett et al. do not teach determining a response characteristic of the base analysis module; characterizing a frequency response of a group of sensors other than the base sensor; and determining a set of calibration coefficients in accordance with at least one of the response characteristic or the frequency response; and including all of the other limitations in the respective independent claims.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Contact Information

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Carol S. W. Tsai whose telephone number is (571) 272-2224. The examiner can normally be reached on Monday-Friday from 8:30 AM to 5:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Marc S. Hoff can be reached on (571) 272-2216. The fax number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 886-217-9197 (toll-free).

Carol S. W. Tsai
Primary Examiner
Art Unit 2857

cswt
July 06, 2005